## Notice of References Cited

Application/Control No.	Applicant(s)/Pater	nt Under
10/758,817	Reexamination MARKS, RICHAR	D L.
Examiner	Art Unit	
KENT WANG	2622	Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-7,106,366	09-2006	Parker et al.	348/222.1
*	В	US-7,061,507	06-2006	Tuomi et al.	345/611
*	υ	US-5,914,723	06-1999	Gajewska, Hania	345/597
*	D	US-6,134,346	10-2000	Berman et al.	382/163
*	Е	US-2003/0012277	01-2003	Azuma et al.	375/240.08
*	н	US-5,557,684	09-1996	Wang et al.	382/107
*	O	US-5,706,364	01-1998	Kopec et al.	382/159
*	н	US-7,161,634	01-2007	Long, Wai Khaun	348/624
*	-	US-7,283,679	10-2007	Okada et al.	382/260
*	7	US-6,556,704	04-2003	Chen, Shoupu	382/154
	К	US-			
	L	US-			
	м	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## NON-PATENT DOCUMENTS

	HON ALL DOGGLETTO				
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)			
	U	Gvili et al., Depth Keying, SPIE Vol 5006(2003), SPIE-IS&T, pp 564-574			
	\ v				
	w				
	×				

A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.